

TEST REPORT

Applicant: HONG KONG LELEGAO TECHNOLOGY CO., LIMITED
Address: 19H Maxgrand Plaza, No.3 Tai Yau Street, San Po Kong, Kowloon, HongKong
Equipment Type: Tablet
Model Name: FLOW 2
Brand Name: OSCAL
Test Standard: 47 CFR Part 15 Subpart B
ANSI C63.4-2014
Sample Arrival Date: Jul. 21, 2026
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ISSUED BY:

Shenzhen BALUN Technology Co., Ltd.

Tested by: Li JunFeng **Checked by:** Zong Liyao

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(Technical Director)

Li JunFeng

Zong Liyao

Jim Liao

Revision History

Version	Issue Date	Revisions
<u>Rev. 01</u>	<u>Aug. 01, 2026</u>	<u>Initial Issue</u>

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1 GENERAL INFORMATION

1.1 Test Laboratory

Name	Shenzhen BALUN Technology Co., Ltd.
Address	601, Building 2, Intelligent Connected Vehicle Industrial Park, No.55, Xiangshan Road, Luotian Community, Yanluo Sub-district, Bao'an District, Shenzhen
Phone Number	+86 755 6685 0100

1.2 Test Location

Name	Shenzhen BALUN Technology Co., Ltd.
Location	☐ Building 2, Intelligent Connected Vehicle Industrial Park, No.55, Xiangshan Road, Luotian Community, Yanluo Sub-district, Bao'an District, Shenzhen, Guangdong
	☒ 1/F., Building B, Ganghongji High-Tech Intelligent Industrial Park, No.1008, Songbai Road, Yangguang Community, Xili Subdistrict, Nanshan District, Shenzhen, Guangdong
Accreditation Certificate	The laboratory is a testing organization accredited by FCC as a accredited testing laboratory. The designation number is CN1196. The certification body is American Association for Laboratory Accreditation (A2LA).

2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	HONG KONG LELEGAO TECHNOLOGY CO., LIMITED
Address	19H Maxgrand Plaza, No.3 Tai Yau Street, San Po Kong, Kowloon, HongKong

2.2 Manufacturer Information

Manufacturer	Shenzhen Doke Electronic Co., LTD
Address	801, Building3, 7th Industrial Zone, Yulv Community, Yutang Road, Guangming District, Shenzhen, China

2.3 General Description for Equipment under Test (EUT)

EUT Name	Tablet
Model Name Under Test	FLOW 2
Series Model Name	N/A
Description of Model name differentiation	N/A
Hardware Version	BND-F868 V2.0
Software Version	FLOW_2_NEU_F868_V1.1_A17_20260825V01
Dimensions (Approx.)	N/A
Weight (Approx.)	N/A

2.4 Ancillary Equipment

Ancillary Equipment 1	Rechargeable Li-ion Battery	
	Brand Name	N/A
	Model No.	U3067133PHVUTL
	Serial No.	N/A
	Capacitance	8300mAh
	Rated Voltage	3.85V
	Limited Voltage	4.4V
	Manufacturer	SHENZHEN UTILITY ENERGY CO., LTD CAUTION.
Ancillary Equipment 2	Power Supply Unit	
	Brand Name	Blackview
	Model No.	QZ-0180AAA00
	Serial No.	N/A
	Rated Input	100-240V~50/60Hz 0.5A
	Rated Output	5.0VDC, 3.0A 15.0W or 9.0VDC, 2.0A 18.0W

		or 12.0VDC, 1.5A 18.0W
	Manufacturer	Guangdong Quanzhi Technology Co., Ltd.
Ancillary Equipment 3	USB Cable	
	Length (Approx.)	1.0 m

2.5 Technical Information

Network and Wireless connectivity	Bluetooth (BR+EDR+BLE) WIFI 802.11a, 802.11b, 802.11g, 802.11n(HT20/HT40), 802.11ac(VHT20/VHT40), 802.11ax(HE20/HE40), 5.8G SRD
Classification of equipment	Class B
The highest internal frequency of EUT	5180MHz

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	47 CFR Part 15 Subpart B	Unintentional Radiators
2	ANSI C63.4-2014	American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Remark
1	Radiated Emission	15.109	Pass	--
2	Conducted Emission, AC Ports	15.107	Pass	--

Note:
 Compared with the EUT of test report Ti-CC26060416-401, the changes of the EUT of this report as below:
 1.Different structure and position of the camera,
 2.The flash is added,
 3.Different antenna size and antenna position.
 4.Different models and brand name.
 Other hardware circuit and software are the same as EUT referred in test report Ti-CC26060416-401.
 Therefore, all the test items were retested in this report.

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
Conducted emissions (9 kHz-150 KHz)	3.36 dB
Conducted emissions (150 kHz-30 MHz)	2.92 dB
Radiated emissions (30 MHz-1 GHz)	4.24 dB
Radiated emissions (1 GHz-6 GHz)	5.10 dB
Radiated emissions (6 GHz-18 GHz)	5.30 dB

4 GENERAL TEST CONFIGURATIONS

4.1 Test Enclosure List

Description	Manufacturer	Model	Serial No.	Length	Description	Use
Laptop	HONOR	N/A	N/A	N/A	N/A	☒
Data connector	HBR	type-c to USB 3.0	N/A	N/A	N/A	☒
USB disk	Sandisk	CZ73-32G	N/A	N/A	N/A	☒
TF Card	N/A	N/A	N/A	N/A	N/A	☒
TYPE-C Earphone	Xiaomi	M1213E1	N/A	N/A	N/A	☒
3.5mm Earphone	N/A	N/A	N/A	N/A	N/A	☒

4.2 Test Configurations

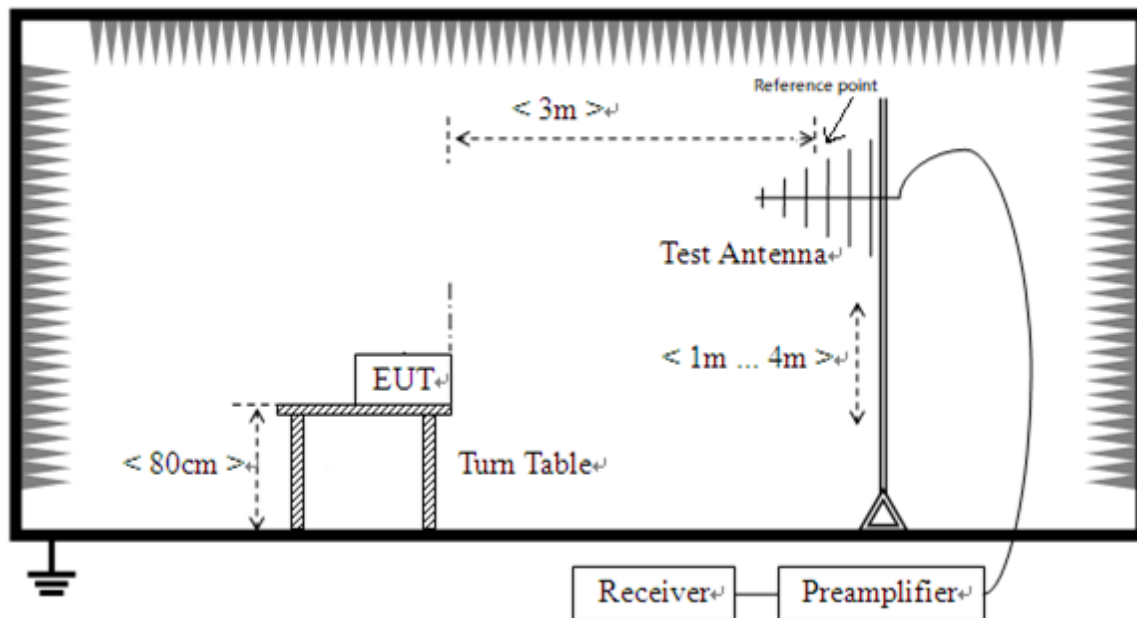
All test modes of EUT are listed in the table below.

Test Mode Configuration	Description
Mode 1	<u>The Front Camera Test Mode</u> EUT + Adapter + USB Cable + Battery + TF Card + 3.5mm Earphone
Mode 2	<u>The Rear Camera Test Mode</u> EUT + Adapter + USB Cable + Battery + TF Card + 3.5mm Earphone
Mode 3	<u>The H-pattern Test Mode</u> EUT + Adapter + USB Cable + Battery + TF Card + 3.5mm Earphone
Mode 4	<u>The Charging Test Mode</u> EUT + Adapter + USB Cable + Battery + TF Card + 3.5mm Earphone
Mode 5	<u>The USB Test Mode</u> EUT + USB Cable + Battery + Laptop + TF Card + 3.5mm Earphone
Mode 6	<u>The Type-C Earphone Test Mode</u> EUT + Type-C Earphone + TF Card
Mode 7	<u>The OTG Test Mode</u> EUT + Battery + Data connector + USB Disk + TF Card + 3.5mm Earphone

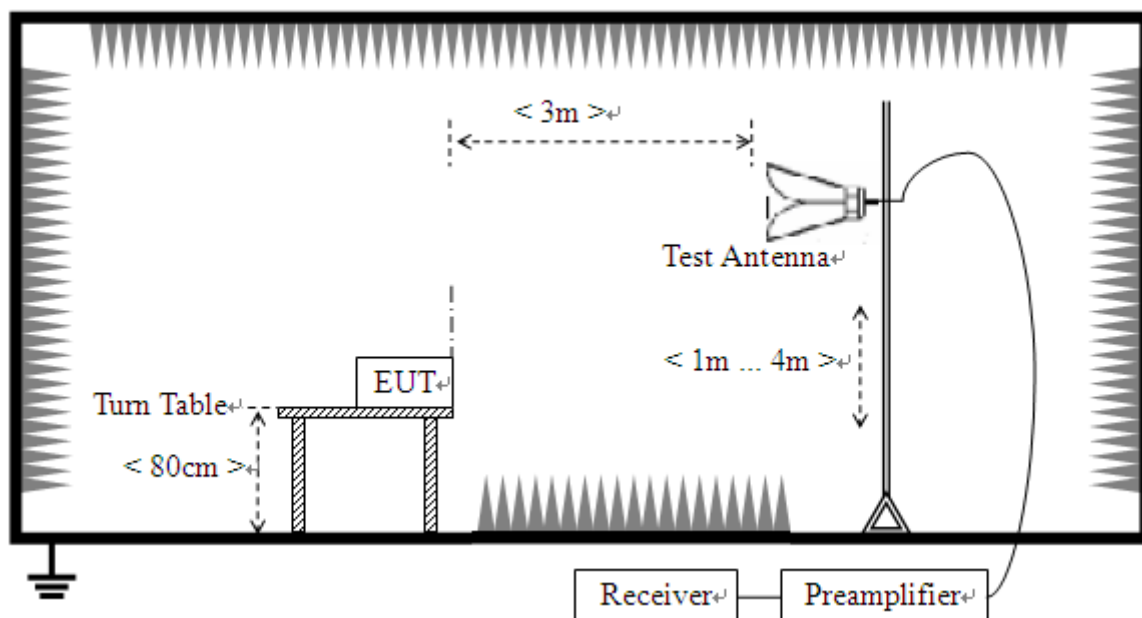
Test Case	Test Mode Configuration	Worst Mode
Radiated Emission	Mode 1~Mode 7	2
Conducted Emission, AC Ports	Mode 1~Mode 5	2
Note: All operation modes were tested, but only test data of the worst mode was presented in this report.		

4.3 Test Setups

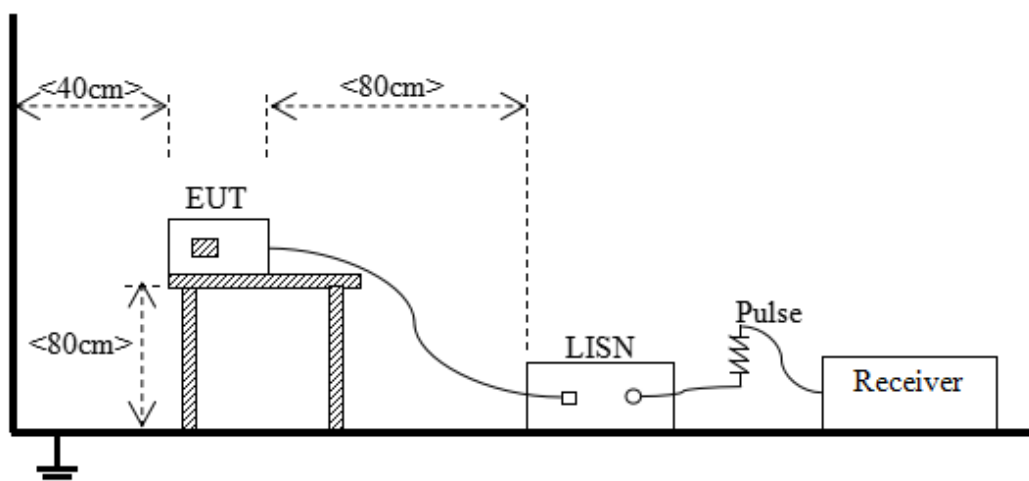
Test Setup 1



Radiated Emission (30 MHz-1 GHz)



Radiated Emission (above 1 GHz)

Test Setup 2

Conducted Emissions, AC Ports

5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency range (MHz)	Class B (at 3 m)		Class A (at 3 m)
	Field Strength ($\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)
30 - 88	100	40	49.5
88 - 216	150	43.5	54
216 - 960	200	46	56.9
Above 960	500	54	60

NOTE:

- 1) Field Strength (dB $\mu\text{V/m}$) = $20 \cdot \log [\text{Field Strength } (\mu\text{V/m})]$.
- 2) In the emission tables above, the tighter limit applies at the band edges.
- 3) For 30 MHz to 1000 MHz, the CISPR quasi-peak is employed.

For above 1000 MHz, according to the requirements of FCC 15.35, unless otherwise specified, the limit on peak radio frequency emissions is 20 dB above the maximum permitted average emission limit applicable to the equipment under test.

Frequency range (GHz)	Class B (at 3 m)			Class A (at 3 m)	
	Field Strength ($\mu\text{V/m}$)	Field Strength Average (dB $\mu\text{V/m}$)	Field Strength Peak (dB $\mu\text{V/m}$)	Field Strength Average (dB $\mu\text{V/m}$)	Field Strength Peak (dB $\mu\text{V/m}$)
1 - F_M	500	54	74	60	80

Note 1: The highest measurement frequency, F_M , in GHz, shall be determined as next Table.

Note 2: Average Class A limit at 3m L_{3m} is determined by the following conversion formula:

$$L_{3m} = L_{10m} + 20 \cdot \log(d_{10m}/d_{3m})$$
Where:
 L_{3m} is Average Class A limit at 3m;
 L_{10m} is Average Class A limit at 10m;
 d_{10m} is Measurement distance in 10m;
 d_{3m} is Measurement distance in 3m.
For this case: $L_{3m} = 49.5 + 20 \cdot \log(10/3) = 60$ (dB $\mu\text{V/m}$).

Highest internal frequency (F_X)	Highest measurement frequency (F_M)
$F_X \leq 108 \text{ MHz}$	1 GHz
$108 \text{ MHz} \leq F_X \leq 500 \text{ MHz}$	2 GHz
$500 \text{ MHz} \leq F_X \leq 1 \text{ GHz}$	5 GHz
$F_X \geq 1 \text{ GHz}$	$5 * F_X$ or 40 GHz, whichever is lower.
Note: F_X is Highest frequency generated or used in the device or on which the device operates or tunes.	

5.1.1.2 Test Setup

Refer to 4.3 section (test setup 1) for radiated emission test, the photo of test setup please refer to ANNEX B.

5.1.1.3 Test Procedure

All Radiated Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

The measurement frequency range is from 30 MHz to the 5th harmonic of the maximum frequency of the EUT internal source. The Turn Table is actuated to turn from 0° to 360° , and both horizontal and vertical polarizations of the Test Antenna are used to find the maximum radiated power. Mid channels on all channel bandwidth verified. Only the worst RB size/offset presented.

Use the following spectrum analyzer settings:

Span = wide enough to fully capture the emission being measured

RBW = 1 MHz for $f \geq 1 \text{ GHz}$, 100 kHz for $f < 1 \text{ GHz}$

VBW $\geq$ RBW

Sweep = auto

Detector function = peak for $f < 1 \text{ GHz}$, peak & RMS Average for $f \geq 1 \text{ GHz}$

Trace = max hold

5.1.1.4 Test Result and Test Equipment List

Please refer to ANNEX A.1.

NOTE:

1. Results (dB μ V/m) = Reading (dB μ V) + Factor (dB/m)

The reading level is calculated by software which is not shown in the sheet

2. Factor (dB/m) = Antenna Factor (dB/m) + Cable Factor (dB) – Amplifier Gain (dB)

3. Margin = Limit - Results

5.1.2 Conducted Emission, AC Ports

5.1.2.1 Test Limit

Frequency range (MHz)	Class A	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	79	66
0.50 - 30	73	60

Frequency range (MHz)	Class B	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- 1) The lower limit shall apply at the band edges.
- 2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50 MHz.

5.1.2.2 Test Setup

Refer to 4.3 section test (test setup 2) for conducted emission, the photo of test setup please refer to ANNEX B.

5.1.2.3 Test Procedure

The EUT is connected to the power mains through a LISN which provides 50 Ω /50 μ H of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30 MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. A device rated for 50/60 Hz operation need not be tested at both frequencies provided the radiated and line conducted emissions are the same at both frequencies.

Use the following spectrum analyzer settings:

RBW = 9 kHz

VBW $\geq$ RBW

Sweep = 10ms

Detector function = peak & Average

Trace = max hold

5.1.2.4 Test Result and Test Equipment List

Please refer to ANNEX A.2.

NOTE:

1. Results (dBμV) = Reading (dBμV) + Factor (dB)

The reading level is calculated by software which is not shown in the sheet

2. Factor = Insertion loss + Cable loss

3. Margin = Limit - Results

ANNEX A TEST RESULTS

A.1 Radiated Emission

Note 1: The symbol of “--” in the table which means not application.

Note 2: For the test data above 1 GHz, according the ANSI C63.4-2014, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

Note 3: The Radiated Emission is required to be investigated to the upper frequency of 5th harmonic of the highest internal frequency of EUT or 40 GHz, whichever is lower. The test results above 18GHz are only noise and are not recorded in the report.

Please refer the document “TR4-01 Test Record for RE.PDF”.

A.2 Conducted Emission, AC Ports

Note: Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. So, The configuration 120 VAC, 60 Hz and 240 VAC, 50 Hz were tested respectively, but only the worst configuration (120 VAC, 60 Hz) shown here.

Please refer the document “TR4-02 Test Record for CE.PDF”.

ANNEX A TEST SETUP PHOTOS

Please refer the document “Ti-CC26070315-AE-1.PDF”.

ANNEX B EUT EXTERNAL PHOTOS

Please refer the document “Ti-CC26070315-AW.PDF”.

ANNEX C EUT INTERNAL PHOTOS

Please refer the document “Ti-CC26070315-AI.PDF”.

Statement

1. The laboratory guarantees the scientificity, accuracy and impartiality of the test, and is responsible for all the information in the report, except the information provided by the customer. The customer is responsible for the impact of the information provided on the validity of the results.
2. The report without China inspection body and laboratory Mandatory Approval (CMA) mark has no effect of proving to the society.
3. For the report with CNAS mark or A2LA mark, the items marked with "☆" are not within the accredited scope.
4. This report is invalid if it is altered, without the signature of the testing and approval personnel, or without the "inspection and testing dedicated stamp" or test report stamp.
5. The test data and results are only valid for the tested samples provided by the customer.
6. This report shall not be partially reproduced without the written permission of the laboratory.
7. Any objection shall be raised to the laboratory within 30 days after receiving the report.

--END OF REPORT--